

1. Scope

This specification is applied to Multilayer Ceramic Chip Capacitor (MLCC) for use in electric equipment for the voltage is ranging from 1KV (Include) to 8KV.

The MLCC support for Lead-Free wave and reflow soldering, and electrical characteristic and reliability are same as before. (This product is compliant with the RoHS.)

2. Parts Number Code

	C 12	206 X		02	К	202	Т	
	(1) (1	2) (3	3)	(4)	(5)	(6)	(7)	
(1)Product					(5)Capacita	ance Toleran	ce	
Product Code	9			_	Code	Tolerance		Nominal Capacitance
С	Multilayer Cer	ramic Chip (Capacitor	_	В	± 0.10 pF		Less Than 10 pF
(2)Chip Size				_	C	± 0.25 pF		(Include 10 pF)
				-	D	± 0.50 pF		
Code	<u> </u>	unit : mm(in	,	_	E	± 1.00 pF		
0201	0.60× 0.30	(.024× .01	,	_	F	± 1.00 %		More Than 10 pF
0402	1.00× 0.50	(.039× .02	,	_	G	± 2.00 %		·
0603	1.60× 0.80	(.063× .03	51)	_	J	± 5.00 %	·	
0805	2.00× 1.25	(.079× .04	.9)		K	± 10.0 %		
1206	3.20× 1.60	(.126× .06	63)	_	М	± 20.0 %		
1210	3.20× 2.50	(.126× .09	8)		Z	+80/-20 %		
1808	4.60× 2.00	(.181× .07	'9)					
1812	4.60× 3.20	(.181× .12	:5)					
1825	4.60× 6.35	(.181× .25	60)	T				
2208	5.70× 2.00	(.220× .19	7)		(6)Rated V	/oltage		
2211	5.70× 2.80	(.220× .11	0)		Code	Ra		ltage (Vdc)
2220	5.70× 5.00	(.220× .19	7)		102		1,00	00
2225	5.70× 6.35	(.220× .25	50)	_	152		1,50	00
				_	202		2,00	00
(3)Temperat	ure Characteristics	s			252		2,50	00

(3) Temperature Characteristics

Code	Temperature	Temperature	Temperature
	Characteristic	Range	Coefficient
N	NPO	-55°C ~+125° C	30 ppm/° C
L	SL	-25°C∼+85° C	+350~-1000ppm
Х	X7R	-55°C ~+125° C	± 15%
В	X5R	-55°C∼+85° C	± 15%
S	X6S	-55°C ~+105° C	± 22%
Y	Y5V	-30°C ~+85° C	+22/-82%
Z	Z5U	+10℃~+85℃	+22/-56%
Е	Y5U	-30°∁ ~+85 °∁	+22/-56%

(4)Capacitance	unit :pico farads(pF)
Code	Nominal Capacitance (pF)
5R0	5.0
120	12.0
151	150.0
102	1,000.0
103	10,000.0
474	470,000.0
105	1,000,000.0
106	10,000,000.0

※. If there is a decimal point, it shall be expressed by an English capital letter R Page : 1/15

302 502

802

(7)Tapping	
Code	Туре
Т	Tape & Reel
В	Bulk

3,000

5,000 8,000



3. Nominal Capacitance and Tolerance

3.1 Standard Combination of Nominal Capacitance and Tolerance

$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$,4.5,5
D (± 0.50 pF) 5,6,7,8,9,10	,4.5,5
E (± 1.00 pF) 6,7,8,9,10	
More Than 10 pF F (±1.00 %) E-12, E-24 series	
G (±2.00 %)	
J (± 5.00 %)	
K (± 10.0 %)	
II X7R/X5R/X7E K (± 10.0 %), M (± 20.0 %) E-3, E-6 series	
Y5V M (± 20.0 %), Z(+80/-20 %) E- 3 series	
Z5U	
Y5U	

3.2 E series(standard Number)

Standard No.		Application Capacitance										
E- 3	1.0			2.2			4.7					
E- 6	1	.0	1	.5	2	.2	3	.3	4	.7	6	.8
E-12	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
E-24	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
	1.1	1.3	1.6	2.0	2.4	3.0	3.6	4.3	5.1	6.2	7.5	9.1

4. Operation Temperature Range

Class	Characteristic	Temperature Range	Reference Temp.
Ι	NPO	-55° C ~ +125°C	25 ℃
	SL	-55°C ~ +125°C	25 ℃
П	X7R	-55° C ~ +125° C	25 ℃
	X5R	-55℃ ~ +85° C	25 ℃
	X6S	-55°C ~ +105°C	25 ℃
	Y5V	-30° C ~ +85 °C	25 ℃
	Z5U	+10℃ ~ +85℃	25 ℃
	Y5U	-30 ℃ ~ +85℃	25 ℃
	Other	-25 ℃ ~ +85℃	25 ℃

5. Storage Condition

Storage Temperature : 5 to 40° C

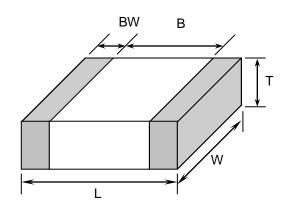
Relative Humidity : 20 to 70 %

Storage Time: 12 months max.

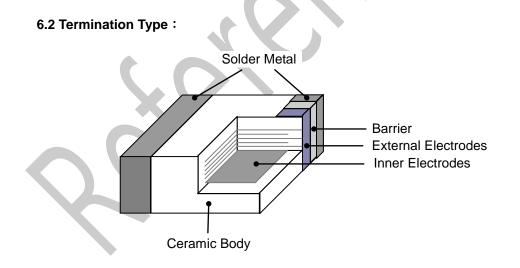


6. Dimensions

6.1 Configuration and Dimension :



					Unit:mm
TYPE	L	W	T (max)	B (min)	BW (min)
0201	0.60± 0.03	0.30± 0.03	0.33	0.20	0.10
0402	1.00± 0.05	0.50± 0.05	0.55	0.30	0.15
0603	1.60± 0.10	0.80± 0.10	1.00	0.40	0.15
0805	2.00± 0.20	1.25± 0.20	1.45	0.70	0.20
1206	3.20± 0.30	1.60± 0.20	1.80	1.50	0.30
1210	3.20± 0.30	2.50± 0.20	2.60	1.60	0.30
1808	4.60± 0.30	2.00± 0.20	2.20	2.50	0.30
1812	4.60± 0.30	3.20± 0.30	3.00	2.50	0.30
1825	4.60± 0.30	6.35±0.40	2.60	2.50	0.30
2208	5.70± 0.40	2.00± 0.20	2.20	3.50	0.30
2211	5.70± 0.40	2.80± 0.40	3.00	3.50	0.30
2220	5.70± 0.40	5.00± 0.40	3.00	3.50	0.30
2225	5.70± 0.40	6.35± 0.40	3.00	3.50	0.30





7. Performance

No.	Item		Spe	ecification	Test Condition		
1	Visua	al	No abnormal ex	terior appearance	Visual inspection		
2	Dimens	ion	See Page 3		Visual inspection		
3	Insulation Resistance		10,000MΩ or 50 Product Whiche		V≦500V, Rated Voltage V>500V, Applied 500Vdc Charge Time ∶ 60sec. Is applied less than 50mA current.		
4	Capacitance	Class I NPO/SL Class II	Within The Speci Within The Speci		$\begin{array}{c c} Class \ I & : \\ \hline NPO/SL \\ \hline Capacitance & Frequency & Voltage \\ \hline C \leq 1000 pF & 1MHz \pm 10\% \\ \hline C > 1000 pF & 1KHz \pm 10\% \\ \hline \end{array}$		
5	Q Tanō	Class I NPO/SL Class II	More Than $30pF : Q \ge 1000$ $30pF \& Below: Q \ge 400 + 20C$ (C : Capacitance , pF)Char.MaximumX7R2.5%Z5U/Y5U4.0%		Class II Frequency Voltage X7R 1KHz±10% 1.0±0.2Vrms Z5U/Y5U 1KHz±10% 1.0±0.2Vrms Perform a heat temperature at 150±5℃ for 30min. then place room temp. for 24±2hr.		
6	0		No dielectric bre mechanical brea		200% /150%/120%/100% Rated Voltage For information which product has which applied voltage, please contact with HEC sales representative. Voltage ramp up rate ≤ 500v/sec for 1~5 sec. charge/discharge Current is less than 50mA.		
7 8	Temperature Capacitance Coefficient Adhesive S of Termin		Char. Temp. Rar NPO $-55^{\circ}C + 12$ SL $-30^{\circ}C + 85$ Char. Temp. Rar X7R $-55^{\circ}C + 12$ Y5U $-30^{\circ}C + 8$ Z5U $+10^{\circ}C + 8$ No indication of p the terminal elect	25°C ± 30 ppm/°C b°C +350~-1000ppm nge Cap. Change(%) 25°C ± 15% 5°C +22% ~-56% 35°C +22% ~-56% beeling shall occur on 1000ppm	Class I : [C2-C1/C1(T2-T1)] × 100% Class II : (C2-C1)/C1 × 100% T1: Standard temperature (25°C) T2: Test temperature C1:Capacitance at standard temperature(25°C) C2: Capacitance at test temperature (T2) Pull force shall be applied for 10± 1 second. ≤ 0603 5N($= 0.5$ Kg·f) >060310N($= 1.0$ Kg·f) N·f		
9	Resistance to Flexure of Substrate	Appear- ance C-Meter	No mechanical d Capacitance Cha Char. NPO SL X7R Y5U/Z5U	-	Bending shall be applied to the 1.0 mm with 1.0 mm/sec. R230 Bending Limit $45\pm1mm$		



Reference sheet

No.	lte	em	Specification		Test Condition
10	Solderability		More than 90% of the is to be soldered new does not come out come	wly, so metal part	Solder Temperature : $245\pm5^{\circ}$ C Dip Time : 5 ± 0.5 sec. Immersing Speed : $25\pm10\%$ mm/s Solder : Lead Free Solder Flux :Rosin Preheat : At 80~120 °C for 10~30sec.
11	Heat	Ance Capacit- ance Q Class I Tan ō Class II Insulation Resistance Withstand	No mechanical dam Characteristic Class I (NPO/SL) Class X7R II Z5U/Y5U To satisfy the specifi To satisfy the specifi To satisfy the specifi	Cap. Change Within ± 2.5% or ±0.25pFwhichever is larger of initial value Within ± 10% Within ± 20% ied initial value ied initial value	Class II capacitor shall be set for 48 ± 4 hours at room temperature after one hour heat treatment at $150 \pm 0/-10^{\circ}$ before initial measure. Preheat : At $150\pm10^{\circ}$ C For $60\sim120$ sec. Dip : Solder Temperature of $260\pm5^{\circ}$ C Dip Time : 10 ± 1 sec. Immersing Speed : $25\pm10\%$ mm/s Flux :Rosin Measure at room temperature after cooling for Class I : 24 ± 2 Hours Class II : 48 ± 4 Hours
12	ture	Voltage Appear- ance Capacit- ance Q Class I Tan ō Class II Insulation Resistance	No mechanical dam Characteristic Class I (NPO/SL) Class X7R II Z5U/Y5U To satisfy the specifi To satisfy the specifi	Cap. ChangeWithin $\pm 2.5\%$ or $\pm 0.25pF$ whicheveris larger of initialvalueWithin $\pm 7.5\%$ Within $\pm 20\%$ ied initial value	Class II capacitor shall be set for 48 ± 4 hours at room temperature after one hour heat treatment at 150 +0/-10 °C before initial measure. Capacitor shall be subjected to five cycles of the temperature cycle as following: $\underbrace{\frac{\text{Step} \text{Temp.}(^{\circ}\text{C}) \text{Time(min)}}{1 \text{Min Rated Temp. +0/-3} 30} \\ 2 25 3 \\ \hline 3 \text{Max Rated Temp. +3/-0} 30 \\ \hline 4 25 3 \\ \hline \end{bmatrix}$ Measure at room temperature after cooling for Class I :24 ± 2 Hrs Class II :48 ± 4 Hrs Solder the capacitor on P.C. board shown in Fig 2. before testing.
13		Appear- ance Capacit- ance Q Class I Tan ō Class II Insulation Resistance	(NPO/SL) = Class X7R V	Cap. ChangeWithin $\pm 5.0\%$ or $\pm 0.5pF$ whichever isarger of initial valueWithin $\pm 15\%$ Within $\pm 30\%$ ± 2350 $275 + 2.5xC$ Maximum 5.0% 5.0%	 2. before testing. Class II capacitor shall be set for 48± 4 hours at room temperature after one hour heat treatment at 150+0/-10 °C before initial measure. Temperature : 40± 2°C Relative Humidity : 90 ~ 95%RH Test Time : 500 +12/-0Hr Measure at room temperature after cooling for Class I : 24 ± 2Hrs Class II : 48 ± 4Hrs Solder the capacitor on P.C. board shown in Fig 2. before testing.



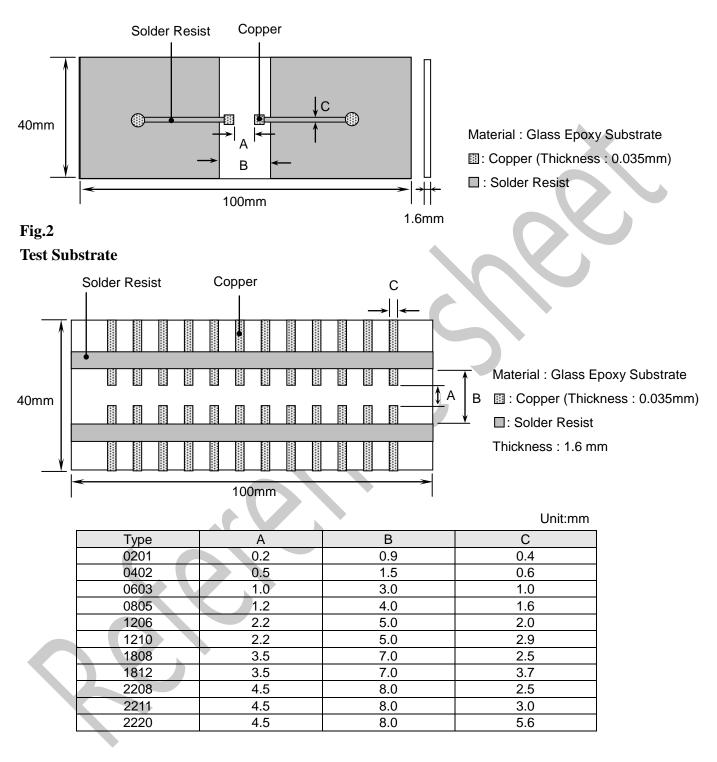
Reference sheet

No.	Iter	n	S	pecifi	cation	Test Condition
14	High Temperature	Appear- ance	No mechanica	l dama	age shall occur	Class II capacitors applied DC voltage (following table) is applied for one hour at maximum
	Load	Capacit-	Characteris	tic	Cap. Change	operation temperature $\pm 3^\circ \!\!\mathbb{C}$ then shall be set for
		ance	Class I		Within ±3.0% or	48±4 hours at room temperature and the initial
			(NPO/SL)		-	measurement shall be conducted.
			Class X7I	<u> </u>	is larger	Voltage Conditioning :
			Class X7I		Within ± 15% Within ± 30%	For information which product has which applied
		Q	More Than 30			voltage, please contact with HEC sales representative.
		Class I			≣ 000 275 + 2.5× C	
		Tan δ	Char.		maximum	Current Applied : 50 mA Max.
		Class ∏	X7R		5.0%	Measure at room temperature after cooling for
			Z5U/Y5U		5.0%	Class I : 24 ± 2 Hours
			1,000MΩ or 50			Class II : 48 ± 4 Hours
		Resistance	smaller.		(C in Farad)	
15	Vibration	Appear-	No mechanica	l dama	age shall occur	Solder the capacitor on P.C. Board shown in
		ance				Fig 2. before testing.
		Capacit-	Characteris	stic	Cap. Change	
		ance			Within $\pm 2.5\%$ or	Vibrate the capacitor with amplitude of 1.5mm P-P changing the frequencies from 10Hz to
			(NPO/SL)		± 0.25pFwhichever is larger	55Hz and back to 10Hz in about 1 min.
			Class X7I	2	Within $\pm 7.5\%$	
			II Z5U/1		Within ± 20%	Repeat this for 2 hours each in 3perpendicular
		Q	To satisfy the s	specifi	ed initial value	directions.
		Class I				
		Tan δ	To satisfy the s	specifi	ed initial value	
		Class II	To poticfy the	nocit:	ad initial value	
		Resistance	To satisfy the s	specifi		
		Resistance				



Fig.1

P.C. Board for Bending Strength Test



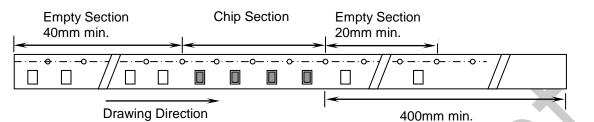


8. Packing

8.1 Bulk Packing

According to customer request.

8.2 Chip Capacitors Tape Packing



8.3 Material And Quantity

Таре	0201	0402	0603/	0805
Material	T≦0.33mm	T≦0.55mm	T≦0.90mm	T>0.90mm
Paper	15,000 pcs/Reel	10,000 pcs/Reel	4,000 pcs/Reel	NA
Plastic	NA	NA	NA	3,000 pcs/Reel

Tape		1206	
Material	T≦0.90mm	0.90 mm $<$ T \leq 1.25 mm	T>1.25mm
Paper	4,000 pcs/Reel	NA	NA
Plastic	NA	3,000 pcs/Reel	2,000 pcs/Reel

Таре		1808/1210	
Material	T≦1.25mm	1.25 mm $<$ T \leq 2.40 mm	T>2.40mm
Paper	NA	NA	NA
Plastic	3000 pcs/Reel	2000 pcs/Reel	500/1,000 pcs/Reel

Tape	1812/2211/2220		1825	2208	
Material	T≦2.20mm	T>2.20mm	T≦2.20mm	T>2.20mm	T≦2.20mm
Paper	NA	NA	NA	NA	NA
Plastic	1000 pcs/Reel	700 pcs/Reel	700 pcs/Reel	400 pcs/Reel	1000 pcs/Reel

NA: Not Available

8.4 Cover Tape Reel Off Force

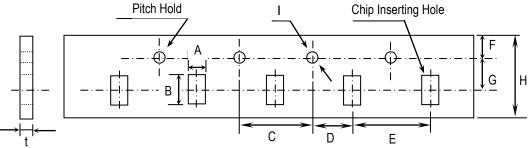
- 8.4.1 Peel-Off Force
 - 5 g·f \leq Peel-Off Force \leq 70 g·f
- 8.4.2 Measure Method





Reference sheet

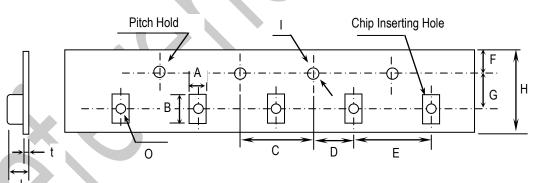
8.5 Paper Tape



					Unit:mm
TYPE	A	В	С	D	E
0201	0.37± 0.1	0.67± 0.1	4.00± 0.1	2.00± 0.05	2.00± 0.1
0402	0.61± 0.1	1.20± 0.1		(
0603	1.10± 0.2	1.90± 0.2			4.00± 0.1
0805	1.50± 0.2	2.30± 0.2			
1206	1.90± 0.2	3.50± 0.2			
1210	2.90± 0.2	3.60± 0.2			

TYPE	F	G	Н		t
0201	1.75± 0.10	3.50± 0.05	8.0± 0.30	φ 1.50 +0.10/-0	1.10 max.
0402					
0603					
0805					
1206					
1210					

8.6 Plastic Tape



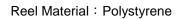
Unit:mm

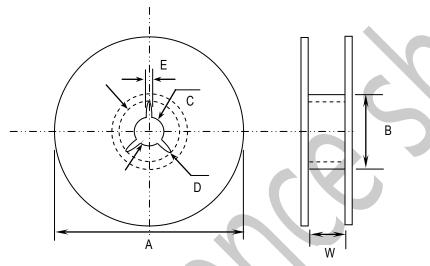
Туре	A	В	С	D	E	F
0805	1.5±0.2	2.3±0.2	4.0± 0.1	2.0± 0.05	4.0± 0.1	1.75± 0.1
1206	1.9±0.2	3.5±0.2				
1210	2.9±0.2	3.6±0.2				
1808	2.5±0.2	4.9±0.2				
1812	3.6±0.2	4.9±0.2			8.0± 0.1	
1825	6.9±0.2	4.9±0.2				
2208	2.5±0.2	6.1±0.2				
2211	3.2±0.2	6.1±0.2				
2220	5.4±0.2	6.1±0.2				
2225	6.9±0.2	6.1±0.2				



Туре	G	Н		J	t	0
0805	3.5± 0.05	8.0± 0.3	φ 1.5+0.1/-0	3.0 max.	0.3 max.	1.0± 0.1
1206						
1210						
1808	5.5± 0.05	12.0 ± 0.3		4.0 max.		1.5± 0.1
1812						
1825						
2208						
2211						
2220						
2225						

8.7 Reel Dimensions





Unit:mm

Туре	А	В	С	D	E	W
0201	φ 382 max	φ 50 min	φ 13± 0.5	φ 21± 0.8	2.0±0.5	10± 0.15
0402						
0603						
0805						
1206						
1210						
1808	φ 178±0.2	φ 60±0.2				13±0.3
1812						
1825						
2208						
2211						
2220						
2225						



Precautionary Notes:

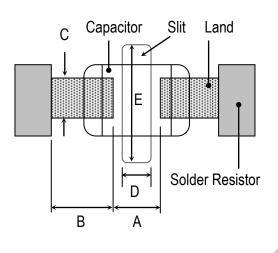
1. Storage

Store the capacitors where the temperature and relative humidity don't exceed 40°C and 70%RH. We recommend that the capacitors be used within 12 months from the date of manufacturing. Store the products in the original package and do not open the outer wrapped, polyethylene bag, till just before usage. If it is open, seal it as soon as possible or keep it in a desiccant with a desiccation agent.

2. Construction of Board Pattern

Improper circuit layout and pad/land size may cause excessive or not enough solder amount on the PC board. Not enough solder may create weak joint, and excessive solder may increase the potential of mechanical or thermal cracks on the ceramic capacitor. Therefore we recommend the land size to be as shown in the following table:

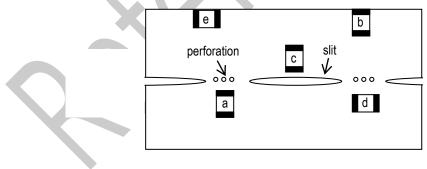
2.1 Size and recommend land dimensions for reflow soldering .



EIA Code	Chip	(mm)		L	and (mm)		
EIA COUE	L	W	А	В	С	D	E
0201	0.60	0.30	0.2~0.3	0.2~0.4	0.2~0.4		
0402	1.00	0.50	0.3~0.5	0.3~0.5	0.4~0.6		
0603	1.60	0.80	0.4~0.6	0.6~0.7	0.6~0.8		
0805	2.00	1.25	0.7~0.9	0.6~0.8	0.8~1.1		
1206	3.20	1.60	2.2~2.4	0.8~0.9	1.0~1.4	1.0~2.0	3.2~3.7
1210	3.20	2.50	2.2~2.4	1.0~1.2	1.8~2.3	1.0~2.0	4.1~4.6
1808	4.60	2.00	2.8~3.4	1.8~2.0	1.5~1.8	1.0~2.8	3.6~4.1
1812	4.60	3.20	2.8~3.4	1.8~2.0	2.3~3.0	1.0~2.8	4.8~5.3
1825	4.60	6.35	2.8~3.4	1.8~2.0	5.1~5.8	1.0~4.0	7.1~8.3
2208	5.70	2.00	4.0~4.6	2.0~2.2	1.5~1.8	1.0~4.0	3.6~4.1
2211	5.70	2.80	4.0~4.6	2.0~2.2	2.0~2.6	1.0~4.0	4.4~4.9
2220	5.70	5.00	4.0~4.6	2.0~2.2	3.5~4.8	1.0~4.0	6.6~7.1
2225	5.70	6.35	4.0~4.6	2.0~2.2	5.1~5.8	1.0~4.0	7.1~8.3

2.2 Mechanical strength varies according to location of chip capacitors on the P.C. board. Design layout of components on the PC board such a way to minimize the stress imposed on the components, upon flexure of the boards in depanelization or other processes.

Component layout close to the edge of the board or the "depanelization line" is not recommended. Susceptibility to stress is in the order of: a>b>c and d>e



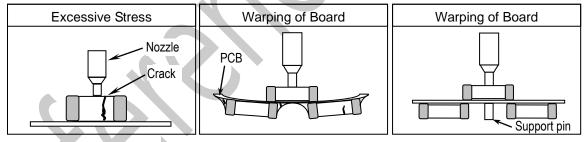


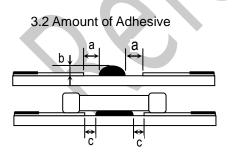
2.3 Layout Recommendation

Example	Use of Common Solder Land	Solder With Chassis	Use of Common Solder Land With Other SMD
Need to Avoid	Lead Wire Chip Solder	Chassis Excessive Solder	Solder Land
Recommendation	Lead Wire Chip Solder Resist	Solder Resist \downarrow \downarrow \downarrow \downarrow \downarrow \downarrow \downarrow \downarrow	

3. Mounting

3.1 Sometimes crack is caused by the impact load due to suction nozzle in pick and place operation. In pick and place operation, if the low dead point is too low, excessive stress is applied to component. This may cause cracks in the ceramic capacitor, therefore it is required to move low dead point of a suction nozzle to the higher level to minimize the board warp age and stress on the components. Nozzle pressure is typically adjusted to 1N to 3N (static load) during the pick and place operation.





Example	080	5 & 120	6
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a	0.2mm min.
b	70 ~ 100 μm
С	Do not touch the solder land

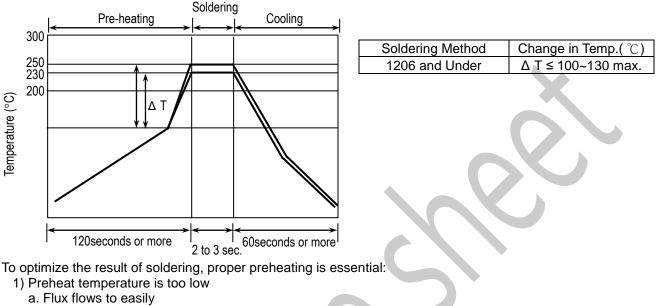


4. Soldering

4.1. Wave Soldering

Most of components are wave soldered with solder at 230 to 250°C. Adequate care must be taken to prevent the potential of thermal cracks on the ceramic capacitors. Refer to the soldering methods below for optimum soldering benefits.

Recommend flow soldering temperature Profile



- b. Possibility of thermal cracks
- 2) Preheat temperature is too high
 - a. Flux deteriorates even when oxide film is removed
 - b. Causes warping of circuit board
 - c. Loss of reliability in chip and other components

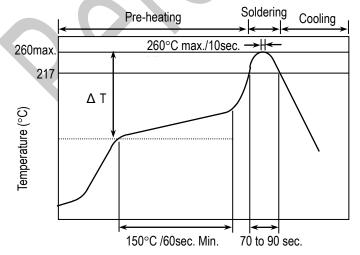
Cooling Condition:

Natural cooling using air is recommended. If the chips are dipped into a solvent for cleaning, the temperature difference (Δ T) between the solvent and the chips must be less than 100°C.

4.2 Reflow Soldering

Preheat and gradual increase in temperature to the reflow temperature is recommended to decrease the potential of thermal crack on the components. The recommended heating rate depends on the size of component, however it should not exceed 3°C/Sec.

Recommend reflow profile for Lead-Free soldering temperature Profile (MIL-STD-202G #210F)



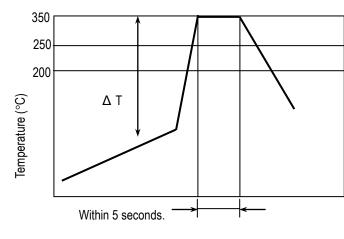
% The cycles of soldering : Twice (max.)

Soldering Method	Change in Temp.($^{\circ}C$)
1206 and Under	Δ T \leq 190 $^{\circ}$ C
1210 and Over	Δ T \leq 130 $^{\circ}$ C



4.3 Hand Soldering

Sudden temperature change in components, results in a temperature gradient recommended in the following table, and therefore may cause internal thermal cracks in the components. In general a hand soldering method is not recommended unless proper preheating and handling practices have been taken. Care must also be taken not to touch the ceramic body of the capacitor with the tip of solder Iron.



Soldering Method	Change in Temp.(°C)
1206 and Under	$\Delta T \leq 150 \ ^{\circ}C$
1210 and Over	Δ T \leq 130 $^{\circ}$ C

How to Solder Repair by Solder Iron

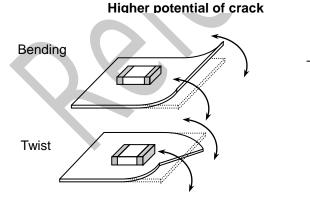
1) Selection of the soldering iron tip

The required temperature of solder iron for any type of repair depends on the type of the tip, the substrate material, and the solder land size.

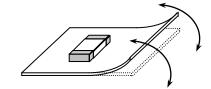
- 2) recommended solder iron condition
 - a.) Preheating Condition : Board and components should be preheated sufficiently at 150°C or over, and soldering should be conducted with soldering iron as boards and components are maintained at sufficient temperatures.
 - b.) Soldering iron power shall not exceed 30 W.
 - c.) Soldering iron tip diameter shall not exceed 3mm.
 - d.) Temperature of iron tip shall not exceed 350°C., and the process should be finished within 5 seconds. (refer to MIL-STD-202G)
 - f.) Do not touch the ceramic body with the tip of solder iron. Direct contact of the soldering iron tip to ceramic body may cause thermal cracks.
 - g.) After soldering operation, let the products cool down gradually in the room temperature.

5. Handling after chip mounted

5.1 Proper handling is recommended, since excessive bending and twist of the board, depends on the orientation of the chip on the board, may induce mechanical stress and cause internal crack in the capacitor.



Lower potential of crack



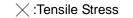
5.2 There is a potential of crack if board is warped due to excessive load by check pin



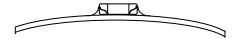


5.3 Mechanical stress due to warping and torsion.

- (a) Crack occurrence ratio will be increased by manual separation.
- (b) Crack occurrence ratio will be increased by tensile force , rather than compressive force.

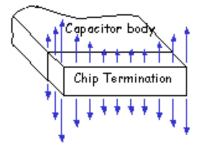


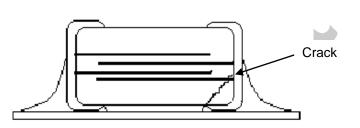
○ :Compressive Stress





Capacitor Stress Analysis



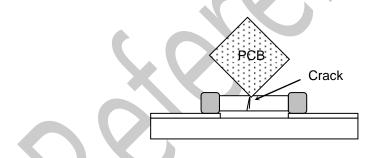


6. Handling of Loose Chip Capacitor

6.1 If dropped the chip capacitor may crack.

Crack Floor

6.2 In piling and stacking of the P.C. boards after mounting for storage or handling, the corner of the P.C. board may hit the chip capacitor mounted on another board to cause crack.



7. Safekeeping condition and period

For safekeeping of the products, we recommend to keep the storage temperature between +5 to +40°C and under humidity of 20 to 70% RH. The shelf life of capacitors is 12 months.

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